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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
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09/741,959LIST OF DOCUMENTS CITED BY APPLICANT  
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VENKATRAMAN

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3624

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JA</i>	AA	6,965,867	11/15/2005	Jameson			
	AB	6,934,931	08/23/2005	Plumer et al.			
	AC	6,826,538	11/30/2004	Kalyan et al.			
	AD	6,745,184	06/01/2004	Choi et al.			
	AE	6,735,572	05/11/2004	Landesmann			
	AF	6,731,998	05/04/2004	Walser et al.			
	AG	6,219,649	04/17/2001	Jameson			
	AH	5,615,109	03/25/1997	Eder			
	AI	5,189,606	02/23/1993	Burns et al.			
	AJ	4,907,170	03/06/1990	Bhattacharya			
	AK	2003/0177103	09/18/2003	Ivanov et al.			
	AL	2002/0116348	08/22/2002	Phillips et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>JA</i>	BA	Andrew B. Gelman et al., "Bayesian Data Analysis", pgs. 439-455, Chapman & Hall/CRC, First Edition 1995, Reprinted 2000.					
<i>21</i>	BB	Hillier, Frederick S., et al., "Introduction to Operations Research", McGraw-Hill, Inc., 1995, Sixth Edition, pages 1-14.					

EXAMINER

*Edmund Lato*

DATE CONSIDERED

*5/11/06*

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